

FQP27P06 P-Channel QFET[®] MOSFET - 60 V, - 27 A, 70 mΩ

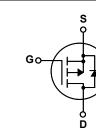
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor[®]'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

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Features

- + 27 A, 60 V, $R_{DS(on)}$ = 70 m Ω (Max.) @ V_{GS} = 10 V, I_{D} = 13.5 A
- Low Gate Charge (Typ. 33 nC)
- Low Crss (Typ. 120 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



Absolute Maximum Ratings T_c = 25°C unless otherwise noted

Symbol	Parameter			FQP27P06	Unit
V _{DSS}	Drain-Source V	oltage		-60	V
I _D	Drain Current	- Continuous (T _C = 25	°C)	-27	A
		- Continuous (T _C = 10	O°C)	-19.1	А
I _{DM}	Drain Current	- Pulsed	(Note 1)	-108	A
V _{GSS}	Gate-Source Voltage			± 25	V
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	560	mJ
I _{AR}	Avalanche Current		(Note 1)	-27	A
E _{AR}	Repetitive Avalanche Energy		(Note 1)	12	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	-7.0	V/ns
PD	Power Dissipation (T _C = 25°C)			120	W
	- Derate above 25°C			0.8	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +175	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds			300	°C
'L				300	U

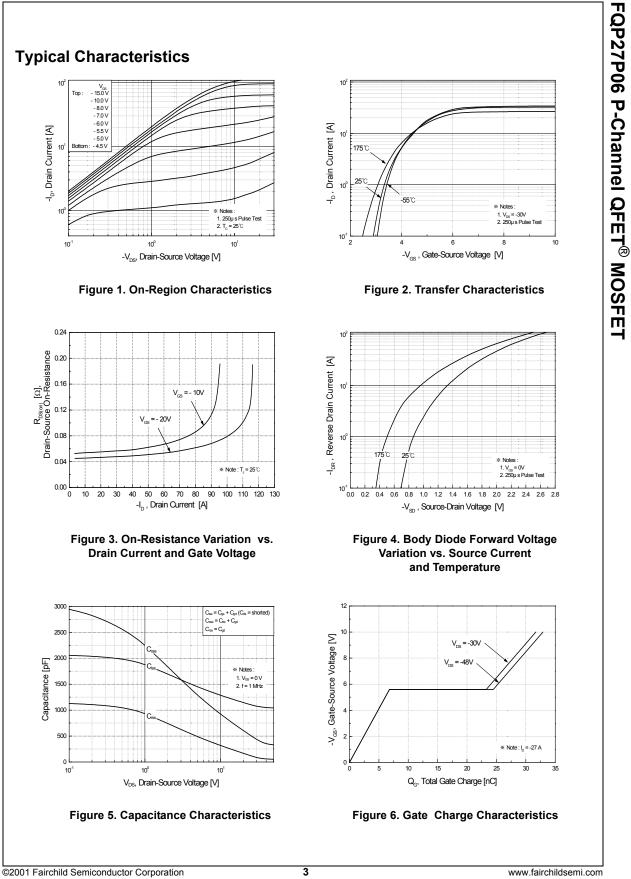
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Thermal Characteristics

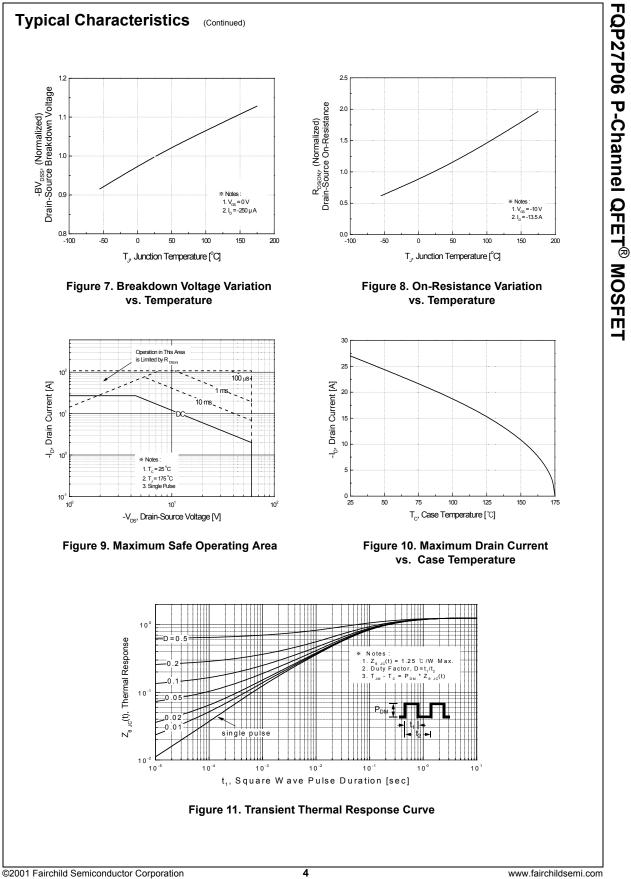
Symbol	Parameter	FQP27P06	Unit °C/W	
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case, Max.	1.25		
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.5	°C/W	
$R_{ hetaJA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W	

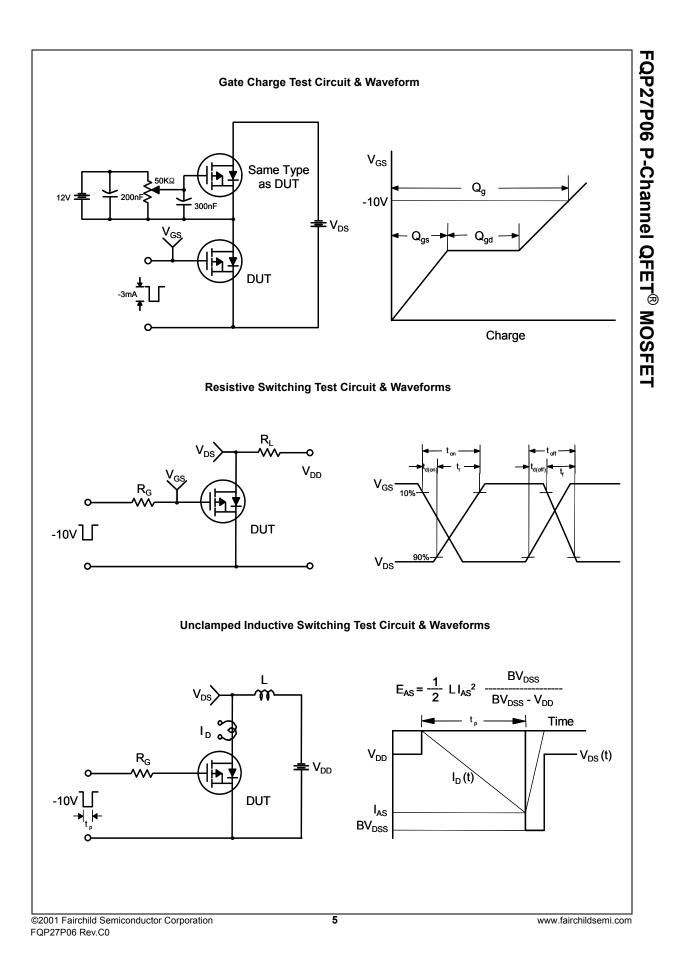
March 2013

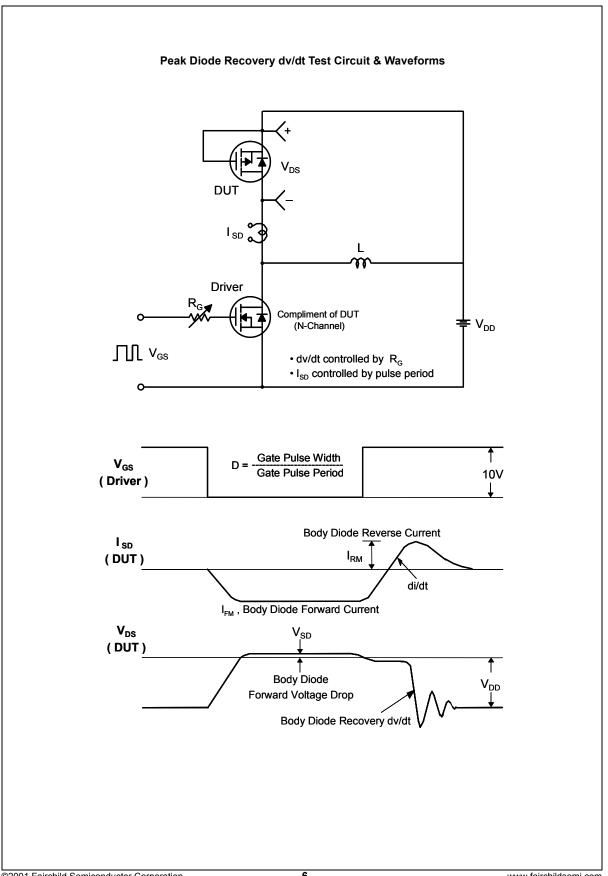
Parameter	Test Conditions	Min	Тур	Max	Unit
iracteristics					
	V _{GS} = 0 V, I _D = -250 μA	-60			V
Breakdown Voltage Temperature Coefficient		C	-0.06		V/°C
	V _{DS} = -60 V, V _{GS} = 0 V			-1	μA
Zero Gate Voltage Drain Current	V _{DS} = -48 V, T _C = 150°C			-10	μA
Gate-Body Leakage Current, Forward $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
Gate-Body Leakage Current, Reverse	V_{GS} = 25 V, V_{DS} = 0 V			100	nA
racteristics					
	V _{DS} = V _{GS} , I _D = -250 μA	-2.0		-4.0	V
Static Drain-Source On-Resistance	•		0.055	0.07	Ω
Forward Transconductance			12.4		S
ic Characteristics	,				
Input Capacitance	V _{DS} = -25 V, V _{GS} = 0 V,		1100	1400	pF
Output Capacitance	f = 1.0 MHz		510	660	pF
Reverse Transfer Capacitance			120	155	pF
ng Characteristics					
Turn-On Delay Time	Vpp = -30 V. lp = -13.5 A.		18	45	ns
Turn-On Rise Time			185	380	ns
Turn-Off Delay Time	0		30	70	ns
Turn-Off Fall Time	(Note 4)	90	190	ns
Total Gate Charge	V _{DS} = -48 V, I _D = -27 A,		33	43	nC
Gate-Source Charge	V _{GS} = -10 V		6.8		nC
Gate-Drain Charge	(Note 4)	18		nC
ource Diode Characteristics a	nd Maximum Ratings				
ource Diode Characteristics a				-27	А
	ode Forward Current			-27 -108	A
Maximum Continuous Drain-Source Dio Maximum Pulsed Drain-Source Diode R	ode Forward Current				
Maximum Continuous Drain-Source Die	ode Forward Current	 		-108	А
	Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse racteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance ic Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance ing Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, \text{ I}_D = -250 \text{ μA}$ Breakdown Voltage Temperature Coefficient $\text{I}_D = -250 \text{ μA}, \text{ Referenced to } 25^{\circ} \text{ M}$ Zero Gate Voltage Drain Current $V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$ Qate-Body Leakage Current, Forward $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ racteristics $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, \text{ I}_D = -250 \text{ μA}$ Static Drain-Source On-Resistance $V_{GS} = -10 \text{ V}, \text{ I}_D = -13.5 \text{ A}$ Forward Transconductance $V_{DS} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}$ ic Characteristics Input CapacitanceInput Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1.0 \text{ MHz}$ Reverse Transfer Capacitance $V_{DD} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}, \text{ R}_G = 25 \Omega$ Turn-On Delay Time Turn-Off Delay Time $V_{DD} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}, \text{ R}_G = 25 \Omega$	$\begin{array}{ c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 \\ \hline Breakdown Voltage Temperature \\ Coefficient & I_D = -250 \ \mu A, Referenced to 25^{\circ}C & \\ \hline V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & \\ \hline V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & \\ \hline Gate-Body \ Leakage Current, Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & \\ \hline Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline \ Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	$\begin{array}{c c c c c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 & & -60 \ I_D = -250 \ \mu A, \ Referenced to 25^{\circ}C & & -0.06 \ V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & & & \ V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & \ V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & \ Gate-Body \ Leakage \ Current, \ Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & & \ Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & \ Tacteristics \ Gate \ Threshold \ Voltage \ V_{DS} = V_{GS}, \ I_D = -250 \ \mu A & -2.0 & \ Static \ Drain-Source & V_{GS} = -10 \ V, \ I_D = -13.5 \ A & & 0.055 \ Forward \ Transconductance & V_{DS} = -30 \ V, \ I_D = -13.5 \ A & & 12.4 \ Tacteristics \ Input \ Capacitance & V_{DS} = -25 \ V, \ V_{GS} = 0 \ V, \ I_D = -13.5 \ A & & 120 \ Tacteristics \ Turn-On \ Delay \ Time & V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Delay \ Time \ Turn-On \ Delay \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Rise \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Rise \ Time \ R_G = 25 \ \Omega & (Note 4) \ Iurn \ 185 \ Iurn-Off \ Fall \ Time \ (Note 4) \ Iurn \ 90 \ Iurn \ V_{DD} = -13.5 \ A \ Iurn \ V_{DD} = -13.5 \ A, \ Iurn-Off \ Fall \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Fall \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -30 \ V, \$	$\begin{array}{c c c c c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 & & & -1 \\ \hline Breakdown Voltage Temperature & I_D = -250 \ \mu A, \ Referenced to 25^{\circ}C & & -0.06 & & & -1 \\ \hline V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & & & -1 & -1 \\ \hline V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate \ Threshold \ Voltage & V_{DS} = V_{GS}, \ I_D = -250 \ \mu A & -2.0 & & -4.0 \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$

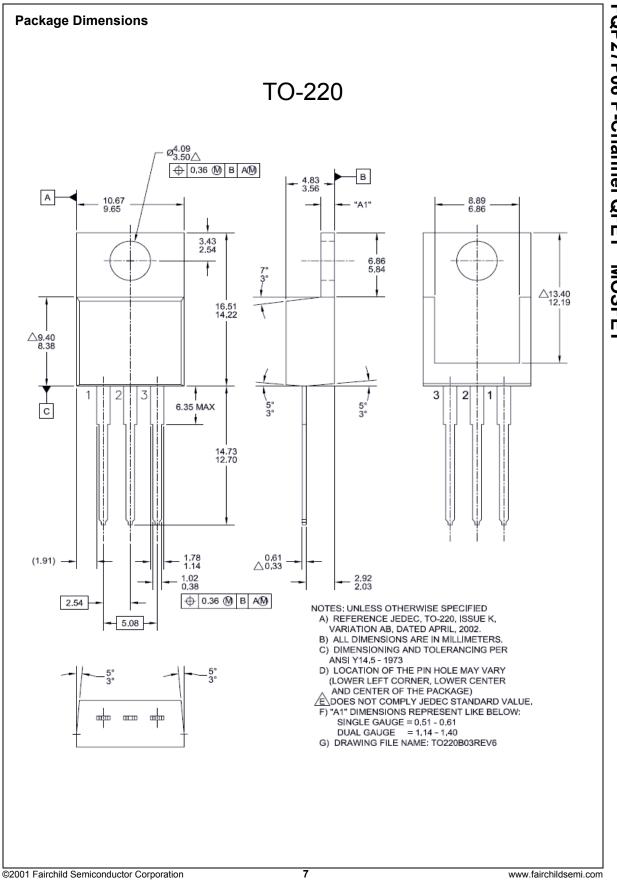


FQP27P06 Rev.C0









FQP27P06 P-Channel QFET® MOSFET



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